

<b>Search Notes</b>  	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10660796	NAGAO, SEIJI
	<b>Examiner</b> Carter, Aaron W	<b>Art Unit</b> 2624

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
382	141-152	12/19/06	AWC
348	125-134, 86-112	12/19/06	AWC
356	237.1-237.6	12/19/06	AWC
705	4	12/19/06	AWC

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
EAST Text Search (USPAT, PGPUB) See Search History Printout	12/19/06	AWC
Inventor Name Search (See PALM Search History Printout, Check Marks Indicate Applications Considered)	12/19/06	AWC
IEEE Search (See Search History Printout)	12/19/06	AWC

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>